Bromley to Address 1991 MRS Fall Meeting

D. Allan Bromley, assistant to the President for science and technology and director of the Office of Science and Technology Policy will address 1991 MRS Fall Meeting attendees in a special plenary session on Monday, December 2. Among other issues, Bromley is expected to report on progress in the national materials initiative under development by the Federal Coordinating Council for Science, Engineering, and Technology (FCCSET).

On leave from his position as Henry Ford II Professor of Physics at Yale University, where he was founder and director of the A.W. Wright Nuclear Structure Laboratory, Bromley is one of the world's leading nuclear physicists. He has carried out pioneering studies on the structure and dynamics of nuclei and is considered the father of modern heavy ion science. He has also played major roles in the development of accelerators, detection systems, and computer-based data acquisition and analysis systems. He has published over 450 papers in science and technology, has edited 18 books, and has received numerous honors and awards, including the National Medal of Science.

An outstanding teacher, Bromley has also been a leader in the national and international science and science policy communities. As chairman of the National Academy's Physics Survey in the early 1970s, he contributed to charting the future of that science in the subsequent decade. As president of the American Association for the Advancement of Science and of the International Union of Pure and Applied Physics, he has been one of the leading spokesmen for U.S. science and for international scientific cooperation.

Prior to his present appointment, Bromley served as a member of the White House Science Council throughout the Reagan administration and as a member of the National Science Board in 1988-1989. As the U.S. chairman for both the Gandhi-Reagan Indo/U.S. and the Sarney-Reagan Brazil/ U.S. Science and Technology Initiatives, he led four Presidential missions to conduct negotiations for bilateral cooperation in science and technology.

Bromley holds BSc and MSc degrees from Queens University, Ontario, Canada. He received a PhD degree in nuclear physics from the University of Rochester and has been awarded 16 honorary degrees from universities in Canada, France, Germany, Italy, South Africa, and the U.S.

Bromley is a member of the National Academy of Sciences, the American Academy of Arts and Sciences, a foreign member of the Brazilian Academy of Sciences, and a Benjamin Franklin Fellow of the Royal Society of Arts (London).



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As part of the 1991 Fall Meeting, a major equipment exhibit is held to display analytical and processing equipment closely paralleling many of the technical symposia.

Complimentary coffee is served in the exhibit hall during breaks in the technical program. A deli lunch is available daily during the show between noon and 1:30 p.m. On Tuesday, MRS highlights the exhibit with a reception from 5:00 - 7:00 p.m. Please join us, meet exhibitors, and take a close look at the latest equipment.

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MRS BULLETIN/NOVEMBER 1991

910138/910010